

Search Notes

Application/Control No.

10/712,643

Examiner

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Applicant(s)/Patent under
Reexamination

FAN ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	136, 142, 152	6/2/2008	TW
375	153, 316	6/2/2008	TW
	UPDATED		
375	147	6/2/2008	TW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	147, 136	6/2/2008	TW
375	142, 152	6/2/2008	TW
375	153, 316	6/2/2008	TW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	6/2/2008	TW
ODP- searched and reviewed from EAST and PALM	6/2/2008	TW
IEEEExplor- Author- Fan Y. P. Hwang S. M. Li H. Y. Chao C. Y.	6/2/2008	TW
IEEEExplor- Advance -despread\$3 and in-phase and quadrature and insert* zero and initial condition	6/2/2008	TW